

December 2006

# FDC638APZ

# P-Channel 2.5V PowerTrench® Specified MOSFET

**–20V, –4.5A, 43m**Ω

### **Features**

- Max  $r_{DS(on)}$  = 43m $\Omega$  at  $V_{GS}$  = -4.5V,  $I_D$  = -4.5A
- Max  $r_{DS(on)}$  = 68m $\Omega$  at  $V_{GS}$  = -2.5V,  $I_D$  = -3.8A
- Low gate charge (8nC typical).
- High performance trench technology for extremely low r<sub>DS(on)</sub>.
- SuperSOT<sup>TM</sup> −6 package:small footprint (72% smaller than standard SO−8) low profile (1mm thick).
- RoHS Compliant



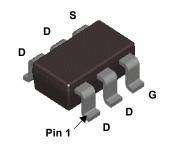
# **General Description**

This P-Channel 2.5V specified MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that has been especially tailored to minimize the on-state resistance and yet maintain low gate charge for superior switching performance

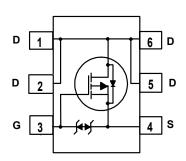
These devices are well suited for battery power applications:load switching and power management,battery charging circuits,and DC/DC conversion.

# **Application**

■ DC - DC Conversion



SuperSOTTM -6



## MOSFET Maximum Ratings TA = 25°C unless otherwise noted

| Symbol                            | Parameter  | Ratings   | Units       |    |
|-----------------------------------|--|-----------|-------------|----|
| V <sub>DS</sub>                   | Drain to Source Voltage                          |           | -20         | V  |
| V <sub>GS</sub>                   | Gate to Source Voltage                           |           | ±12         | V  |
| 1                                 | Drain Current -Continuous                        | (Note 1a) | -4.5        | ^  |
| 'D                                | -Pulsed  |           | -20         | A  |
| D                                 | Power Dissipation                                | (Note 1a) | 1.6         | W  |
| $P_D$                             | Power Dissipation                                | (Note 1b) | 0.8         | VV |
| T <sub>J</sub> , T <sub>STG</sub> | Operating and Storage Junction Temperature Range |           | -55 to +150 | °C |

#### **Thermal Characteristics**

| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient | (Note 1a) | 78  | °C/W |
|-----------------|---|-----------|-----|------|
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient | (Note 1b) | 156 | C/VV |

#### **Package Marking and Ordering Information**

| Device Marking | Device    | Reel Size | Tape Width | Quantity   |
|----------------|-----------|-----------|------------|------------|
| .638Z          | FDC638APZ | 7"        | 8mm        | 3000 units |

# **Electrical Characteristics** $T_J = 25^{\circ}C$ unless otherwise noted

| Symbol                                | Parameter                                 | Test Conditions   | Min | Тур  | Max       | Units |
|---------------------------------------|---|---|-----|------|-----------|-------|
| Off Chara                             | ecteristics                               |   |     |      |           |       |
| $BV_{DSS}$                            | Drain to Source Breakdown Voltage         | $I_D = -250 \mu A, V_{GS} = 0 V$                        | -20 |      |           | V     |
| ΔBV <sub>DSS</sub><br>ΔΤ <sub>J</sub> | Breakdown Voltage Temperature Coefficient | $I_D$ = -250 $\mu$ A, referenced to 25°C                |     | -9.4 |           | mV/°C |
| I <sub>DSS</sub>                      | Zero Gate Voltage Drain Current           | $V_{DS} = -16V,$<br>$V_{GS} = 0V$ $T_{J} = 55^{\circ}C$ |     |      | -1<br>-10 | μА    |
| I <sub>GSS</sub>                      | Gate to Source Leakage Current            | $V_{GS} = \pm 12V, V_{DS} = 0V$                         |     |      | ±10       | μΑ    |

### **On Characteristics**

| $V_{GS(th)}$                           | Gate to Source Threshold Voltage                            | $V_{GS} = V_{DS}, I_{D} = -250 \mu A$             | -0.4 | -0.8 | -1.5 | V     |
|--|---|---|------|------|------|-------|
| $\frac{\Delta V_{GS(th)}}{\Delta T_J}$ | Gate to Source Threshold Voltage<br>Temperature Coefficient | $I_D = -250\mu\text{A}$ , referenced to 25°C      |      | 2.9  |      | mV/°C |
|  |   | $V_{GS} = -4.5V, I_D = -4.5A$                     |      | 37   | 43   |       |
| r <sub>DS(on)</sub>                    | Static Drain to Source On Resistance                        | $V_{GS} = -2.5V, I_D = -3.8A$                     |      | 52   | 68   | mΩ    |
|  |   | $V_{GS} = -4.5V$ , $I_D = -4.5A$ , $T_J = 125$ °C |      | 50   | 72   |       |
| I <sub>D(on)</sub>                     | On-State Drain Current                                      | $V_{GS} = -10V, V_{DS} = -4.5A$                   | -20  |      |      | Α     |
| 9 <sub>FS</sub>                        | Forward Transconductance                                    | $V_{DS} = -10V$ , $I_{D} = -4.5A$                 |      | 18   |      | S     |

# **Dynamic Characteristics**

| C <sub>iss</sub> | Input Capacitance            | V - 40V V - 0V                            | 750 | 1000 | pF |
|------------------|------------------------------|---|-----|------|----|
| C <sub>oss</sub> | Output Capacitance           | $V_{DS} = -10V, V_{GS} = 0V,$<br>f = 1MHz | 155 | 210  | pF |
| C <sub>rss</sub> | Reverse Transfer Capacitance | 1 - 11/11/12                              | 130 | 195  | pF |

## Switching Characteristics (Note 2)

| t <sub>d(on)</sub>  | Turn-On Delay Time            |  | 6  | 12 | ns |
|---------------------|-------------------------------|--|----|----|----|
| t <sub>r</sub>      | Rise Time                     | $V_{DD} = -5V, I_{D} = -4.5A$<br>$V_{GS} = -4.5V, R_{GEN} = 6\Omega$ | 20 | 31 | ns |
| t <sub>d(off)</sub> | Turn-Off Delay Time           | V <sub>GS</sub> 4.5V, K <sub>GEN</sub> - 052                         | 48 | 77 | ns |
| t <sub>f</sub>      | Fall Time                     |  | 47 | 72 | ns |
| $Q_{g(TOT)}$        | Total Gate Charge             | $V_{GS} = 0V \text{ to } -4.5V$ $V_{DD} = -5V$                       | 8  | 12 | nC |
| $Q_{gs}$            | Gate to Source Gate Charge    | I <sub>D</sub> = -4.5A   | 2  |    | nC |
| $Q_{gd}$            | Gate to Drain "Miller" Charge |  | 2  |    | nC |

# **Drain-Source Diode Characteristics**

| $I_{r} = -4.5A \text{ di/dt} = 100A/\text{us}$  | I <sub>S</sub>  | Maximum Continuous Drain-Source Diode Forward Current |   |      | -1.3 | Α  |
|---|-----------------|---|---|------|------|----|
| $I_{c} = -4.5A$ , di/dt = 100A/us   | $V_{SD}$        | Source to Drain Diode Forward Voltage                 | $V_{GS} = 0V, I_{S} = -1.3A$ (Note 2)   | -0.8 | -1.2 | V  |
| Q <sub>rr</sub> Reverse Recovery Charge   1 <sub>F</sub> = -4.5A, dirut = 100A/μS   13   20   1 | t <sub>rr</sub> | Reverse Recovery Time                                 | L = 4.50 di/dt = 1000/                  | 24   | 36   | ns |
|   | Q <sub>rr</sub> | Reverse Recovery Charge                               | T <sub>F</sub> = -4.5A, α//αι = 100A/μs | 13   | 20   | nC |

Notes:
 1: R<sub>0JA</sub> is the sum of the junction-to-case and case-to-ambient resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.R<sub>0JC</sub> is guaranteed by design while R<sub>0CA</sub> is determined by user's board design.



a. 78°C/W when mounted on a 1 in² pad of 2 oz copper on FR-4 board.



b. 156°C/W when mounted on a minimum pad of 2 oz copper.

<sup>2:</sup> Pulse Test: Pulse Width <  $300\mu s$ , Duty cycle < 2.0%.

## Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

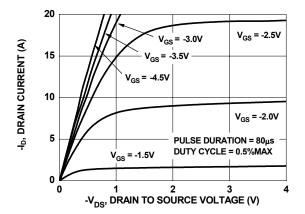


Figure 1. On-Region Characteristics

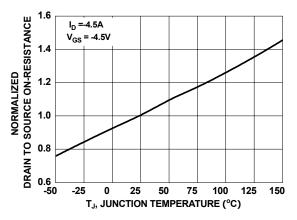


Figure 3. Normalized On-Resistance vs Junction Temperature

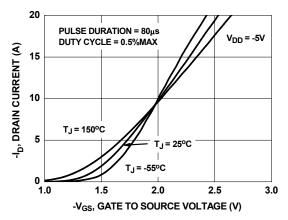


Figure 5. Transfer Characteristics

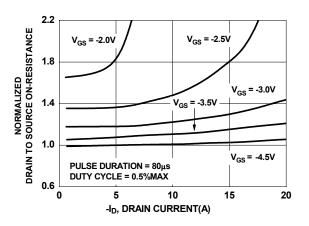


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

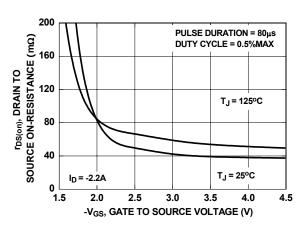


Figure 4. On-Resistance vs Gate to Source Voltage

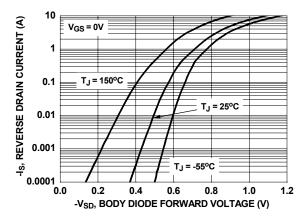


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# **Typical Characteristics** $T_J = 25^{\circ}C$ unless otherwise noted

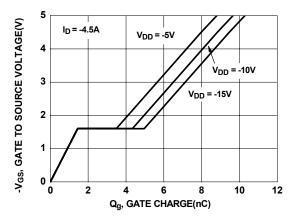


Figure 7. Gate Charge Characteristics

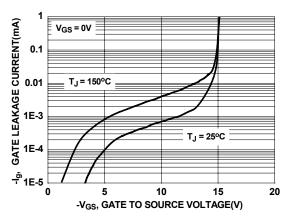


Figure 9. Gate Leakage Current vs Gate to Source Voltage

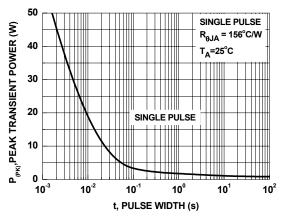


Figure 11. Single Pulse Maximum Power Dissipation

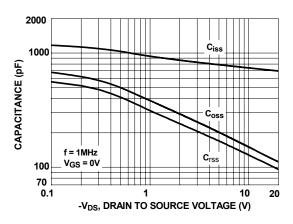


Figure 8. Capacitance vs Drain to Source Voltage

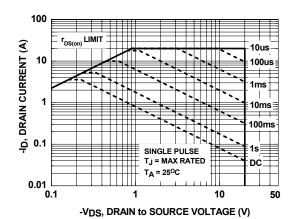


Figure 10. Forward Bias Safe Operating Area

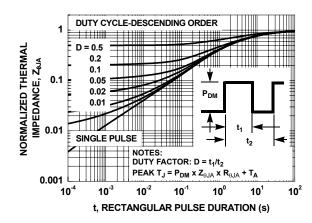


Figure 12. Transient Thermal Response Curve

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